N-channel TrenchMOS logic level FET

Rev. 01 — 10 September 2008

Preliminary data sheet

1. Product profile

1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in industrial and communications applications.

1.2 Features and benefits

High efficiency due to low switching and conduction losses

1.3 Applications

- Class-D amplifiers
- DC-to-DC converters

1.4 Quick reference data

Table 1. Quick reference

- Suitable for logic level gate drive sources
- Motor control
- Server power supplies

Table 1.	QUICK reference						
Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 150 °C		-	-	30	V
I _D	drain current	$T_{mb} = 25 \text{ °C}; V_{GS} = 10 \text{ V};$ see <u>Figure 1</u> ; see <u>Figure 3</u> ;	[1]	-	-	100	A
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	-	97	W
Dynamic	characteristics						
Q _{GD}	gate-drain charge	$\label{eq:VGS} \begin{array}{l} V_{GS} = 4.5 \text{ V}; \text{ I}_{D} = 10 \text{ A}; \\ V_{DS} = 12 \text{ V}; \text{ see } \underline{\text{Figure } 14}; \\ \text{see } \underline{\text{Figure } 15} \end{array}$		-	7.5	-	nC
Static ch	aracteristics						
R _{DSon}	drain-source on-state resistance	V _{GS} = 10 V; I _D = 15 A; T _j = 25 °C; see <u>Figure 12</u>		-	1.56	2	mΩ

[1] Continuous current is limited by package.



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2. Pinning information

Table 2.	Pinning	information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		_
2	S	source	mb ()	
3	S	source		
4	G	gate	Q	
mb	D	mounting base; connected to drain	$\begin{array}{c} \begin{array}{c} \\ \end{array} \\ 1 \end{array} \begin{array}{c} 2 \end{array} \begin{array}{c} 3 \end{array} \begin{array}{c} 4 \end{array}$	mbb076 S
			SOT669 (LFPAK)	

3. Ordering information

Table 3. Orderin	ng information		
Type number	Package		
	Name	Description	Version
PSMN2R0-30YL	LFPAK	Plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669

4. Limiting values

Table 4.Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

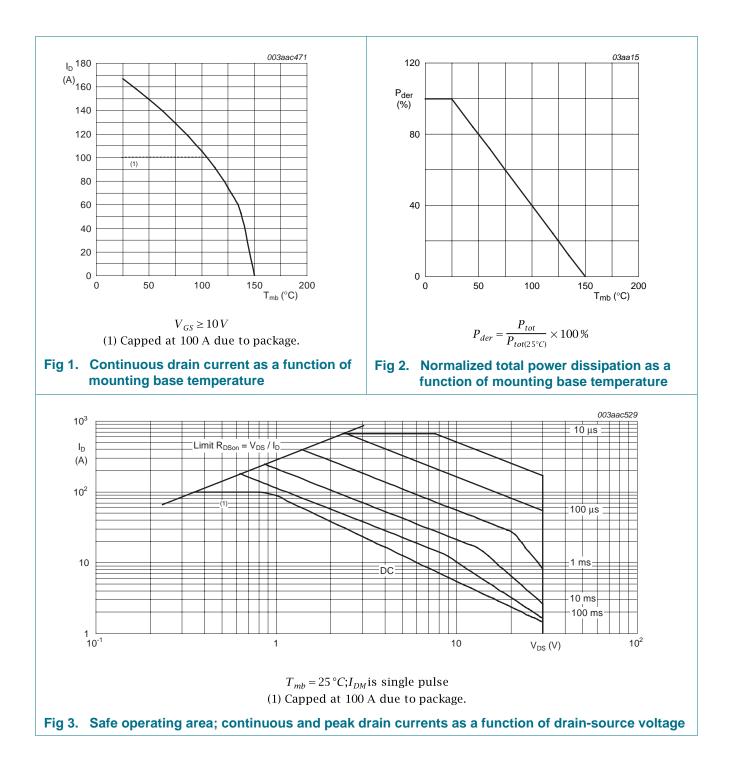
Symbol	Parameter	Conditions		Min	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 150 °C		-	30	V
V _{DGR}	drain-gate voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$		-	30	V
V _{GS}	gate-source voltage			-20	20	V
I _D	drain current	V _{GS} = 10 V; T _{mb} = 100 °C; see <u>Figure</u> <u>1;</u>	[1]	-	100	А
		V_{GS} = 10 V; T_{mb} = 25 °C; see <u>Figure 1</u> ; see <u>Figure 3</u> ;	[1]	-	100	А
I _{DM}	peak drain current	t _p ≤ 10 μs; pulsed; T _{mb} = 25 °C; see <u>Figure 3</u>		-	667	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	97	W
T _{stg}	storage temperature			-55	150	°C
Tj	junction temperature			-55	150	°C
Source-dra	in diode					
Is	source current	T _{mb} = 25 °C;	[1]	-	100	А
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$		-	667	А
Avalanche	ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 100 A; $V_{sup} \le 30$ V; R_{GS} = 50 Ω ; unclamped		-	151	mJ

[1] Continuous current is limited by package.

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5. Thermal characteristics

ymbol	Parameter	Conditions			Min	Тур	Max	Unit
h(j-mb)	thermal resistance from junction to mounting base			-	1.28	K/W		
10 📼							003aac481	
Z _{th(j-mb)}								
(K/W)								
1								
	= 0.5							
-	0.2							
-	.05							
	0.02				P		$\delta = \frac{t_p}{T}$	
10-2								
	single shot							
F		+++++				→ t _p ←		
10 ⁻³						₩, T	→	
10 ⁻⁶	10 ⁻⁵	10 ⁻⁴	10 ⁻³	10 ⁻²	10	-1 t	_p (s) 1	
10	10	10	10	10	10		P	

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6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
-	racteristics	Conditions	IAILLI	тур	Wax	Unit
			20			V
V _{(BR)DSS}	drain-source breakdown voltage	$I_D = 250 \ \mu\text{A}; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ}\text{C}$	30	-	-	V
		$I_D = 250 \ \mu A; V_{GS} = 0 \ V; T_j = -55 \ ^{\circ}C$	27	-	-	V
V _{GS(th)}	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C}; \text{ see}$ Figure 10; see Figure 11	1.3	1.7	2.15	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 150 \text{ °C}; \text{ see}$ Figure 10	0.65	-	-	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = -55 \text{ °C}; \text{ see}$ Figure 10	-	-	2.45	V
DSS	drain leakage current	V _{DS} = 30 V; V _{GS} = 0 V; T _i = 25 °C	-	-	1	μA
		V _{DS} = 30 V; V _{GS} = 0 V; T _i = 150 °C	-	-	100	μA
I _{GSS}	gate leakage current	V _{GS} = 16 V; V _{DS} = 0 V; T _i = 25 °C	-	-	100	nA
		V _{GS} = -16 V; V _{DS} = 0 V; T _i = 25 °C	-	-	100	nA
R _{DSon}	drain-source on-state resistance	$V_{GS} = 4.5 \text{ V}; \text{ I}_{D} = 15 \text{ A}; \text{ T}_{j} = 25 \text{ °C}; \text{ see}$ Figure 12	-	2.15	3.2	mΩ
	$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 150 \text{ °C}; \text{ see}$ Figure 13	-	-	3.3	mΩ	
		$V_{GS} = 10$ V; $I_D = 15$ A; $T_j = 25$ °C; see Figure 12	-	1.56	2	mΩ
R _G	gate resistance	f = 1 MHz	-	0.75	-	Ω
	characteristics					
Q _{G(tot)}	total gate charge	I_D = 10 A; V_{DS} = 12 V; V_{GS} = 10 V; see Figure 14; see Figure 15	-	64	-	nC
		$I_D = 0 \text{ A}; \text{ V}_{DS} = 0 \text{ V}; \text{ V}_{GS} = 10 \text{ V}$	-	59	-	nC
		I_D = 10 A; V_{DS} = 12 V; V_{GS} = 4.5 V; see Figure 14	-	30	-	nC
Q _{GS}	gate-source charge	I _D = 10 A; V _{DS} = 12 V; V _{GS} = 4.5 V; see	-	9.8	-	nC
Q _{GD}	gate-drain charge	Figure 14; see Figure 15	-	7.5	-	nC
Q _{GS(th)}	pre-threshold gate-source charge		-	6.6	-	nC
Q _{GS(th-pl)}	post-threshold gate-source charge		-	3.2	-	nC
V _{GS(pl)}	gate-source plateau voltage	V _{DS} = 12 V; see <u>Figure 14</u> ; see <u>Figure 15</u>	-	2.34	-	V
C _{iss}	input capacitance	V _{DS} = 12 V; V _{GS} = 0 V; f = 1 MHz;	-	3980	-	pF
C _{oss}	output capacitance	T _j = 25 °C; see <u>Figure 16</u>	-	857	-	pF
C _{rss}	reverse transfer capacitance		-	347	-	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 12 \text{ V}; \text{ R}_{L} = 0.5 \Omega; \text{ V}_{GS} = 4.5 \text{ V};$	-	39	-	ns
t _r	rise time	$R_{G(ext)} = 4.7 \Omega$	-	65	-	ns
t _{d(off)}	turn-off delay time		-	63	-	ns
t _f	fall time			28	-	ns

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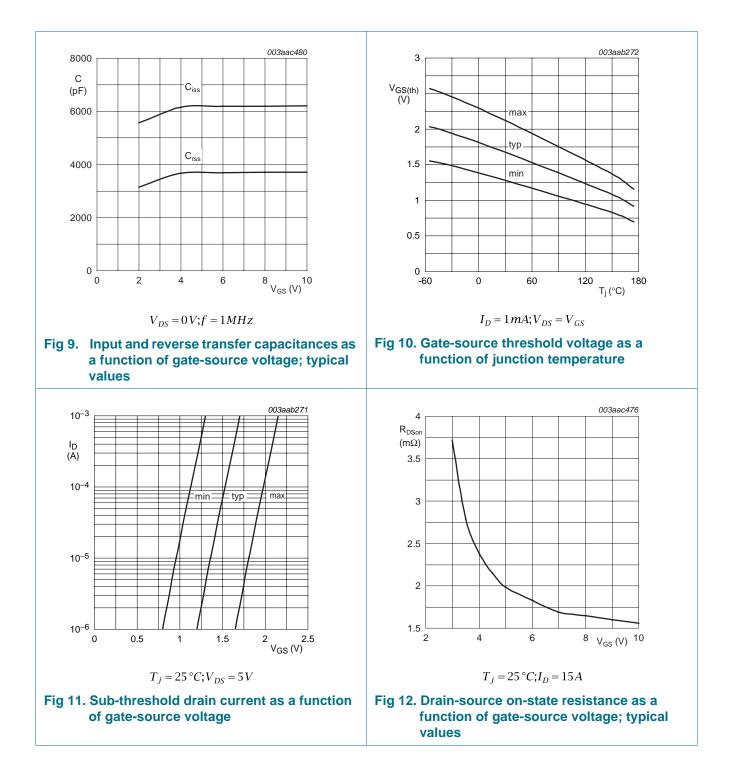
mbol	Parameter	Conditions		Min	Тур	Мах	Un
urce-drai	n diode						
)	source-drain voltage	I _S = 25 A; V _{GS} = 0 V; T <u>Figure 17</u>	_j = 25 °C; see	-	0.88	1.2	V
	reverse recovery time		0 A/s; V _{GS} = 0 V;	-	43	-	ns
	recovered charge	V _{DS} = 20 V		-	49	-	nC
80 I _D (A) 60 40 20 0 0	T _j = 150 °C	003aac470	150 I _D (A) 10 10 10 10 10 10 10 50 0 0 0 2		GS (V) = 3	003aac474	
fur	$V_{DS} = 10V$ ansfer characteristics action of gate-source lues	s: drain current as a		$f_j = 25 ^{\circ}C; t_p$ aracteristi	= 300 <i>µs</i> cs: dra	V _{DS} (V)	nt as
fur	ansfer characteristics	003aac475	T Fig 6. Output cha function of values	$f_j = 25 ^{\circ}C; t_p$ aracteristi	= 300 µs	V _{DS} (V)	nt as pica

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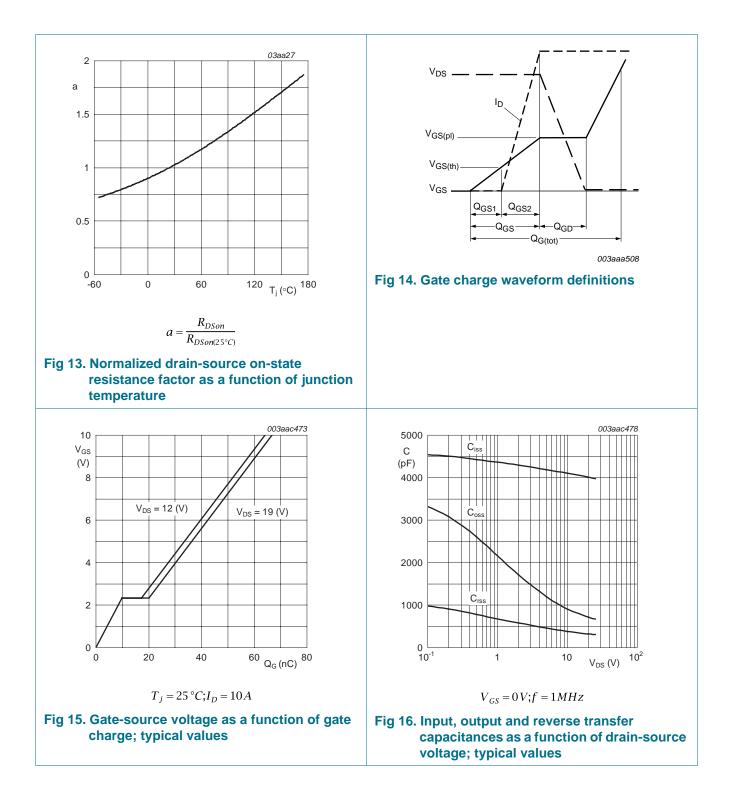
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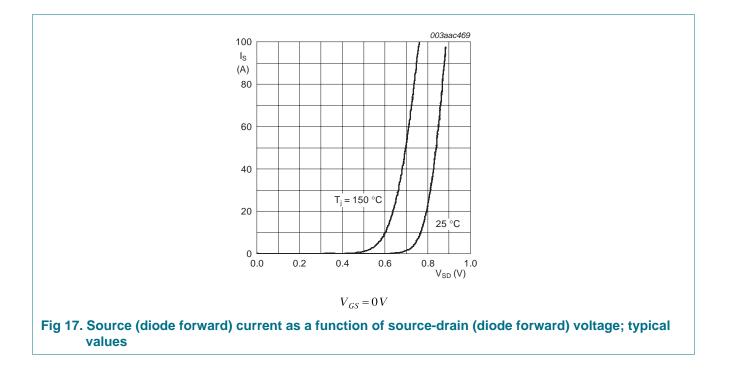


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7. Package outline

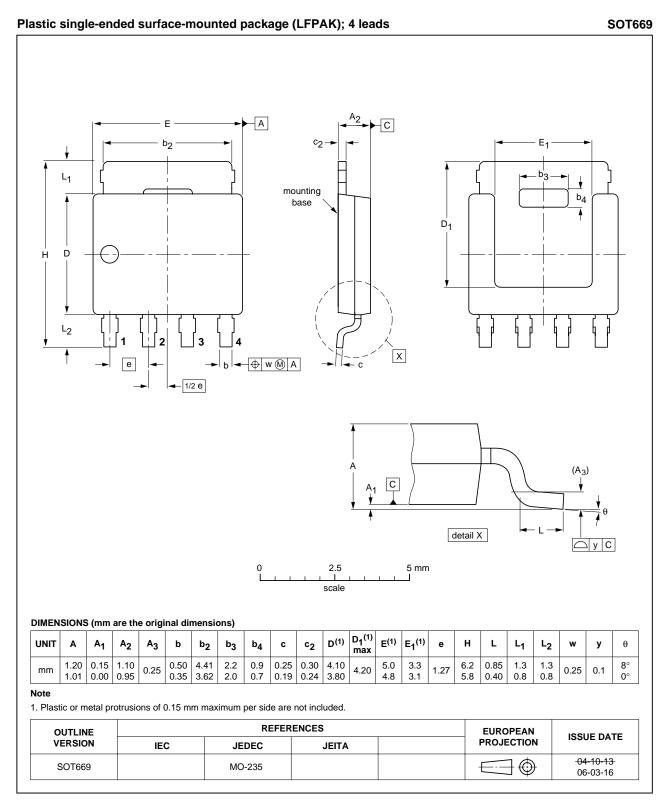


Fig 18. Package outline SOT669 (LFPAK)

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8. Revision history

Table 7. Revision his	tory			
Document ID	Release date	Data sheet status	Change notice	Supersedes
PSMN2R0-30YL_1	20080910	Preliminary data sheet	-	-

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9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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[2] The term 'short data sheet' is explained in section "Definitions".

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